PTO-1449

Sheet 1 of 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

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Attorney Docket No.:	Application No.:
8013-1139	09/944,186
Applicant: YAMAGUCHI et al.	
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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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	FISCHER et al., "Direct imaging of the spectral emission characteristic of an InGaN/GaN-ultraviolet light-emitting diode by highly spectrally and spatially resovled electroluminescence and photoluminescence microscopy", APPLIED PHYSICS LETTERS, AMERICAN INSTITUTE OF PHYSICS, NEW YORK, US, November 29, 1999, pp. 3440-3442, XP012024140
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EXAMINER:	DATE CONSIDERED
	12/20/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* English language abstract provided for the Examiner's convenience